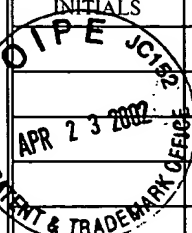
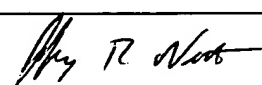


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| INFORMATION DISCLOSURE CITATION IN AN APPLICATION | | | | ATTY. DOCKET NO. 50006-128 | | SERIAL NO. 09/977,994 | |
| (PTO-1449) | | | | APPLICANT Makoto NAGATA, et al. | | | |
| | | | | FILING DATE October 17, 2001 | | GROUP 2857 | |
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| EXAMINER'S INITIALS | PATENT NO. | DATE | NAME | CLASS | SUBCLASS | FILING DATE | |
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| FOREIGN PATENT DOCUMENTS | | | | | | | |
| EXAMINER'S INITIALS | PATENT NO. | DATE | COUNTRY | CLASS | SUBCLASS | Translation | |
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.